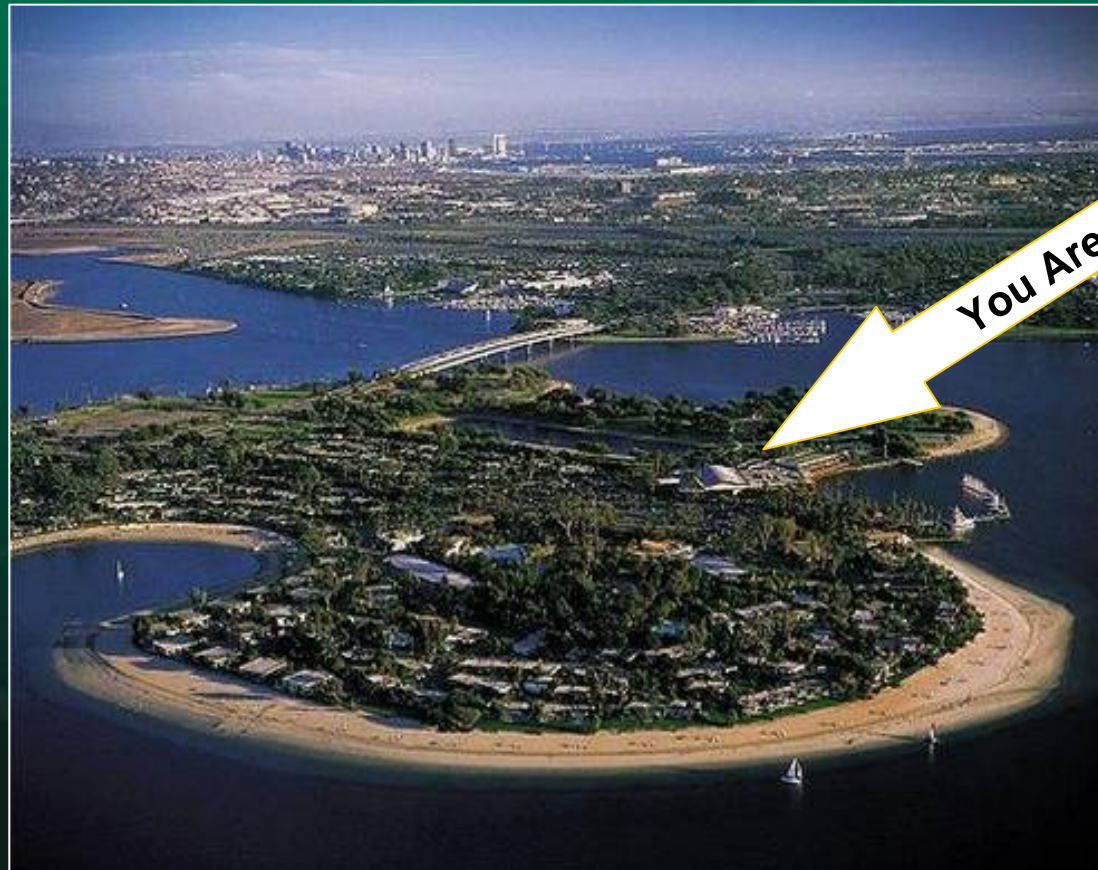# Welcome to the IEEE SW Test Workshop

Jerry Broz, Ph.D.
SW Test General Chair

June 7 to 10, 2009
San Diego, CA USA

19th Annual SWTW 2009

You Are Here !

Paradise Point and Spa, San Diego, CA

IEEE SW-Test Workshop

- **SW Test IS a Probe Technology Forum …**

  - It is *"THE"* Conference for Wafer Test Professionals
  - Practical solutions to real problems
  - A balance mixture of semiconductor manufacturer and supplier presentations

- **Informal Conference …**

  - Great social activities and informal discussions
  - Meet new people and have a little fun !

IEEE SW-Test Workshop

- **Sponsored by the IEEE Components, Packaging and Manufacturing Technology (CPMT) Society**

- **Leading international forum for scientists and engineers engaged in the research, design and development of revolutionary advances in micro-systems packaging and manufacture.**

CPMT

IEEE COMPONENTS, PACKAGING AND
MANUFACTURING TECHNOLOGY SOCIETY

What's New for 2009 ?

- **Technical Program**
  - 9 Technical Sessions with 31 Podium Presentations

- **Products / Services EXPO – 2009**
  - 28 full size booths

- **Corporate Support Program**
  - Five corporate supporters … THANKS !

- **Major Website Redesign and Facelift**

- **New Committee Members**
  - Darren James, Rudolph Technologies
  - Roger Hayward, Cascade Microtech
  - Jan Martens, NXP Semiconductor
  - Rod Martens, FormFactor, Inc.
  - Frank Pietzschmann, Qimonda AG

SWTW Website Redesign

- **You talked ... and we listened.**

- **New Look for Easier Navigation**

- **Central Repository**
  - Past presentations
  - Online registration
  - Current news for SW Test Workshop
  - Mailing list sign-up

- **Tremendous on-line resource !!**

Corporate Supporter Program
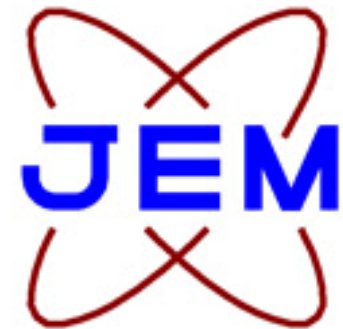
A few words about 2009

- **Overall Reduced Attendance (~65 to 70% reduction)**
  - General economic recession
  - Downturn in semiconductor and related sectors
  - Continued H1N1 swine flu warnings

- **Contracted resort minimums must be met during workshop**
  - Reserved room block
  - Food and beverages
  - IEEE / SW Test <u>PAY</u> the difference !

E N J O Y !

We're Moving for 2010 ...

Rancho Bernardo Inn, San Diego, CA
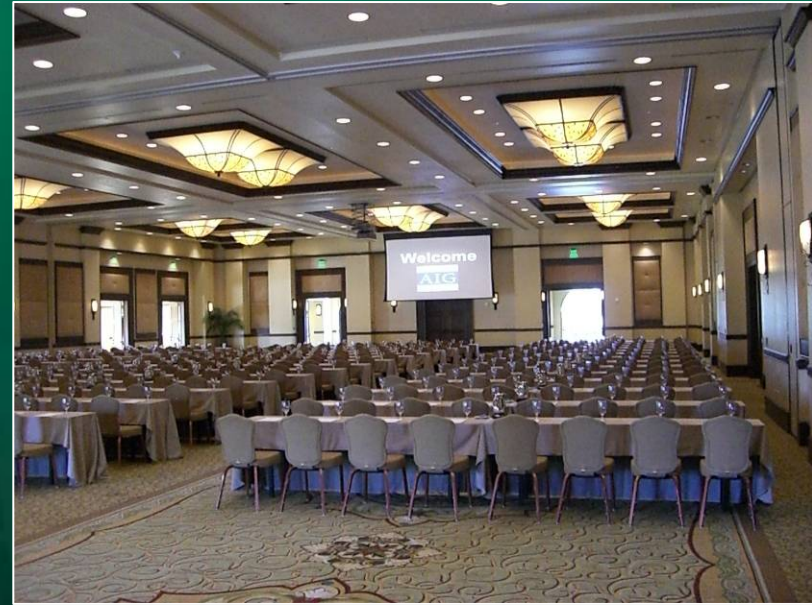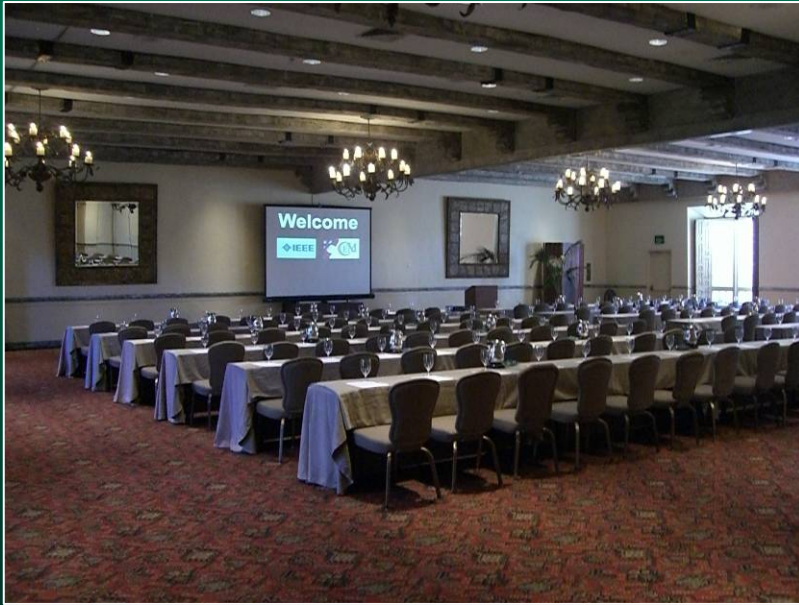
20th Annual SWTW 2010

"Who's To Blame … ?"

- **Organization and Technical Program …**
  - Jerry Broz, Ph.D., International Test Solutions, General Chair
  - Brett Crump, Micron Technology, Program Chair
  - Maddie Harwood, CEM Inc, Registration and Finance Chair
  - Meredith Griffith, CEM Inc., Exhibits / Registration Coordinator

Program Committee and Steering Committee

- Ken Karklin, AeroVironment
- Patrick Mui, JEM-America
- Fred Taber, BiTS Workshop
- Darren James, Rudolph Technologies
- Warren "Stu" Crippen, Intel

- Roger Hayward, Cascade Microtech
- Jan Martens, NXP Semiconductor
- Rod Martens, Ph.D., FormFactor, Inc.
- Frank Pietzschmann, Qimonda AG
- Rey Rincon, Freescale Semiconductor

Technical Program / Agenda

- **Sunday, June 8, 2008**
  - Tutorial on "Tool Metrology"
  - Registration and Cocktails
  - Dinner
  - Probe Year In Review
  - Keynote Presentation

"Economics Driving Test Technology"

Risto Pukkha
President
VLSI Research, Inc.

Technical Program / Agenda

- **Monday, June 9**
  - Continental Breakfast
  - Welcome and Large Array Probing
  - Signal Integrity
  - Lunch
  - Sort Floor Data Analysis
  - High Temperature Probing Challenges
  - Reception / EXPO-2009 / Dinner
  - Networking at Barefoot Bar or Vendor Events

Technical Program / Agenda

- **Tuesday, June 10**
  - Controlling Contact Resistance
  - RF Probing Challenges
  - BBQ Lunch on the Paradise Lawn
  - Damage Control and Low Force Probing
  - EXPO-2009 in Paradise Ballroom
  - Reception, Dinner, and **Casino Royal** in Sunset Ballroom !
    - Gambling, networking, prizes, FUN !

Tuesday Social

- **Gambling, Prizes, FUN !**
- **Relaxed networking**
- **Dinner and Reception**

Technical Program / Agenda

- **Wednesday, June 11**
  - Continental Breakfast
  - Standards and Methods
  - Probe Potpourri
  - Awards and Adjourn Conference
  - Lunch in Bay View and Dockside Rooms

Recognition & Awards

- **Best Overall Presentation**

- **Best Data Presented**

- **Most "Inspirational" Presentation**

- **Best Presentation, Tutorial in Nature**

- **Other "Special Awards"**

SWTW-2008 Awards

Best Overall Presentation

"Methodologies for Assessing On-line Probe Process Parameters"

Jan Martens
NXP Semiconductors (Hamburg)

Simon Allgaier
FeinMetall, GmbH

Jerry Broz, Ph.D.
International Test Solutions

Best Data Presentation

"VFPP-Very Fine Pitch 60uM Probe Card Technology Optimization"

John D. Wolfe
James Tong
Norman Armendariz, Ph.D.
Texas Instruments, Inc.

SWTW-2008 Awards

Most Inspirational Presentation
"Automatic Probe Assembly Machine"

Jung-pyo Chun
Dave Oh
Kyung-hwan Kim
TSE Co., Ltd.

Best Presentation, Tutorial in Nature
"Real-World Avalanche Testing of Single-Die, Wafers, Hybrid Modules, and Packaged Devices"

Steven T. Clauter
Integrated Technology Corporation

Taichi Ukai
Taitech

SWTW-2008 Awards

Best Poster Presentation
"Clean the WAFER, NOT the PROBE CARD!"

Terence Q. Collier
CVInc

David B. Rennie and Chuck Lhota
Air Products & Chemicals

Lifetime Achievement Award
Presented to …

Don Snow
CEO Emeritus
Founder of Applied Precision, LLC.

The "Special" Award

"What A Load Of Crap !"

For the Poorest Disguised Sales Pitch

*"What happens at SWTW stays at SWTW !"*

IEEE SW Test EXPO 2009

(⭐ <u>Corporate Supporter</u>)

- Aceris-3d Inspection, Inc.
- Acme Technology, Inc.
- ⭐ <u>Advanced Probing Systems, Inc.</u>
- Air Products
- Ardent Concepts, Inc.
- ⭐ <u>BucklingBeam Solutions, LLC</u>
- ⭐ <u>Electro Scientific Industries, Inc. "esi"</u>
- Elite E/M, Inc.
- ERS America
- Everett Charles Technologies
- Feinmetall GmbH
- FormFactor, Inc.
- ICOS Vision Systems / KLA-Tencor
- Integrated Test Corporation
- Interconnect Devices, Inc.

- ⭐ <u>International Test Solutions, Inc.</u>
- ⭐ <u>JEM America Corp.</u>
- Left Coast Instruments
- MicroProbe
- NHK Spring Co., Ltd
- Probe Logic
- Rudolph Technologies, Inc.
- Spire Manufacturing
- SUSS MicroTec
- SV Probe, Inc. - An Ellipsiz Company
- T.I.P.S. Messtechnik GmbH
- Taconic
- Technoprobe, America
- Tokyo Electron Limited
- Vermont Mold & Tool
- Wentworth Laboratories, Inc.

Don't Get Lost !

Exhibits

EXPO Reception

Conference And Social
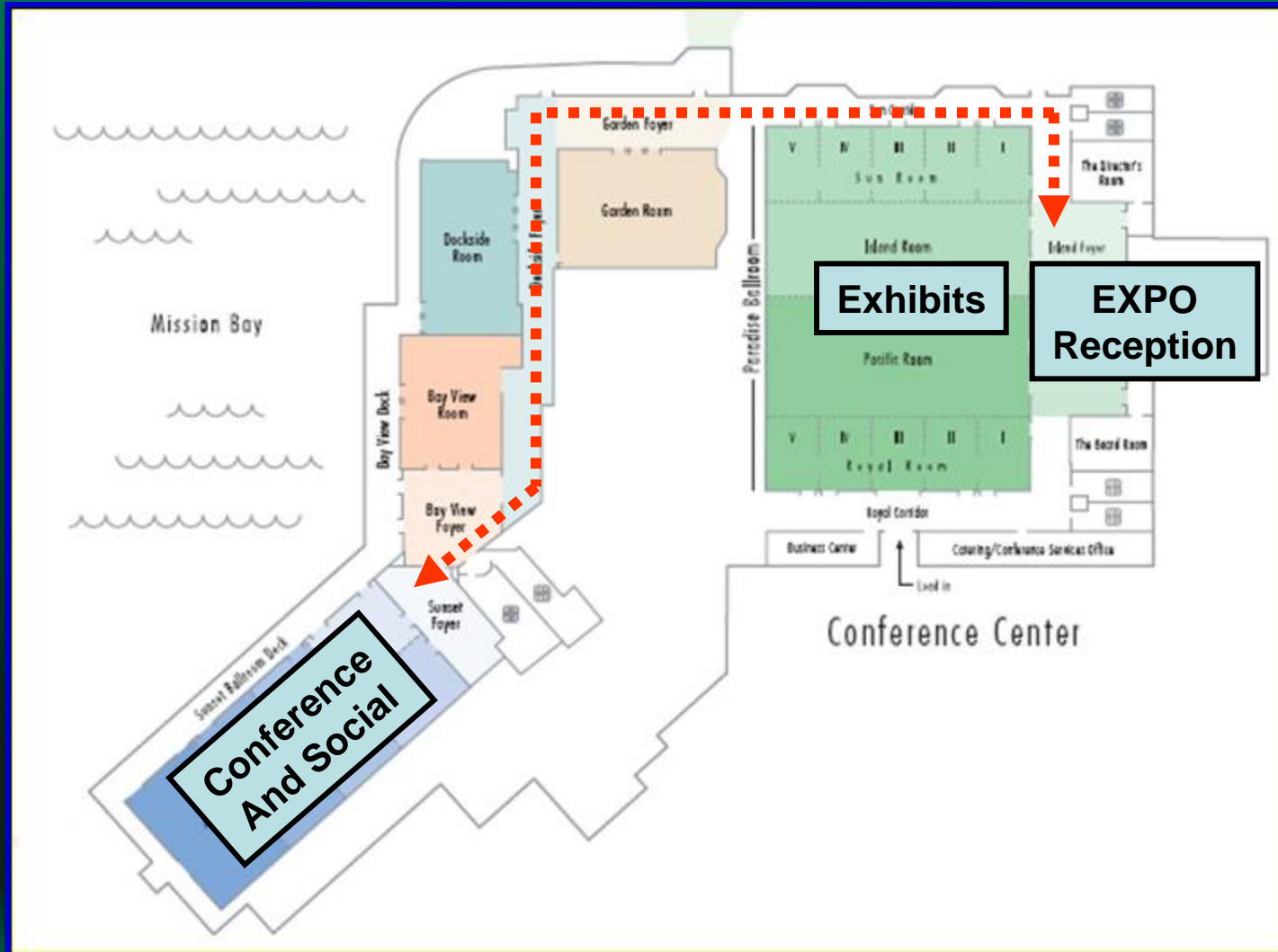
Don't Get Lost in Paradise !

Barefoot Bar

Exhibits

Conference

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Want to Learn More ?

- Burn In & Test Socket Workshop
  Mesa, Arizona

- IS-Test Workshop
  Freising, Germany

- Electronic Components and Technology Conference
  San Diego, CA

Silence your cell phone !!!